

Express Mail Label No.: EV 292 459 657 US

Date of Deposit: February 25, 2004

| | | | | | | | |
|--|---|----|---|---|--|--|--|
| FORM PTO-1449/A and B (Modified) INFORMATION DISCLOSURE STATEMENT BY APPLICANT | | | | APPLICATION NO.: Not Yet Assigned | | ATTY. DOCKET NO.: A0312.70522US00 | |
| | | | | FILING DATE: Not Yet Assigned <u>Here with 2/25/04</u> | | CONFIRMATION NO.: Not Yet Assigned | |
| | | | | APPLICANT: Richard P. Schubert | | | |
| | | | | GROUP ART UNIT: Not Yet Assigned <u>2827</u> | | EXAMINER: Not Yet Assigned <u>David Lam</u> | |
| Sheet | 1 | of | 1 | | | | |

U.S. PATENT DOCUMENTS

| Examiner's Initials | Cite No. | U.S. Patent Document | | Name of Patentee or Applicant of Cited Document | Date of Publication or of issue of Cited Document MM-DD-YYYY |
|------------------------|-------------|----------------------|--------------|--|--|
| | | Number | Kind Code | | |
| DL | A1 | 5,559,745 | | Banik et al. | 09/24/1996 |
| DL | A2 | 5,920,517 | | Wendell | 07/06/1999 |
| DL | A3 | 5,930,185 | | Wendell | 07/27/1999 |
| | | | | | |
| | | | | | |
| | | | | | |
| | | | | | |
| | | | | | |

FOREIGN PATENT DOCUMENTS

| Examiner's Initials | Cite No. | Foreign Patent Document | | | Name of Patentee or Applicant of Cited Document (not necessary) | Date of Publication of Cited Document MM-DD-YYYY | Translation (Y/N) |
|------------------------|-------------|-------------------------|--------|--------------|---|---|----------------------|
| | | Office/ Country | Number | Kind Code | | | |
| | | | | | | | |
| | | | | | | | |
| | | | | | | | |
| | | | | | | | |
| | | | | | | | |
| | | | | | | | |
| | | | | | | | |

OTHER ART — NON PATENT LITERATURE DOCUMENTS

| Examiner's Initials | Cite No | Include name of the author (in CAPITAL LETTERS) title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, relevant page(s), volume-issue number(s), publisher, city and/or country where published. | Translation (Y/N) |
|------------------------|------------|---|----------------------|
| DL | C1 | "Data Retention System", IBM Technical Disclosure Bulletin, May 1975, pp. 1 2; | |
| DL | C2 | "Checking Random Access Memory", IBM Technical Disclosure Bulletin, March 1978, pp. 1-2; | |
| DL | C3 | Ding-Ming Kwai et al., "Detection of SRAM Cell Stability by Lowering Array Supply Voltage", Proceedings of the 9 th Asian Test Symposium, 2000 IEEE; | |
| DL | C4 | Anne Meixner et al., "WEAK WRITE TEST MODE: An SRAM Cell Stability Design For Test", pp. 309-318, IEEE 1996 | |

| | |
|--------------------------|---------------------------------|
| EXAMINER <i>DA Fu</i> | DATE CONSIDERED <i>11/05</i> |
|--------------------------|---------------------------------|

#EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

*a copy of this reference is not provided as it was previously cited by or submitted to the office in a prior application, Serial No. __, filed __, and relied upon for an earlier filing date under 35 U.S.C. 120 (continuation, continuation-in-part, and divisional applications).